

Anchor Semiconductor releases a new design layout analysis product for design based yield enhancement

An integrated tool for IC manufacturing to locate, monitor and specially handle the most sensitive process/yield patterns/regions of any given designs.

Santa Clara, Calif.—February 28, 2011—Anchor Semiconductor, Inc. announced today the release of a new product NanoScope™ DPE (Design Pattern Explorer) to enrich its existing pattern centric product portfolios. NanoScope™ DPE is a design based yield management and enhancement tool for production usage.

As IC industry moves towards smaller and smaller technology nodes, the design complexity increases drastically. With existing tools/products, it is a great challenge to design a hotspot free IC layout; as a matter of fact, the hard-to-process hotspot patterns will increase due to the increased design complexity. In addition, how to effectively locate, monitor and specially handling those hotspots is equally challenging in IC manufacturing. After working closely with our leading Foundry and IDM partners and beta testing, newly released NanoScope™ DPE is designed to help our customers to meet that challenge.

NanoScope™ DPE is the natural extension of Anchor Semiconductor's existing pattern centric product family, which provides two major capabilities for manufacturing applications—one is whole chip layout partition and pattern signature analysis; and the other is advanced pattern search. The whole chip layout partition and pattern signature analysis/ranking will zero-in to the most process/yield sensitive regions, which serves as effective guides for metrology/inspection strategy. Advanced pattern search, on the other hand, will zero-in on complex 2D hotspot patterns. Those 2D complex patterns have proven or suspected process/yield sensitivity based on data collected in real production.

“Our customers recognize DPE's importance in manufacturing of advanced technology nodes, especially in applications of locating, monitoring and special handling yield sensitive complex hotspot patterns.” Anchor Semiconductor's President Dr. Chenmin Hu said, after his recent meetings with our partners. “We will continue to work closely with our customers to enhance design knowledge based yield management.”

NanoScope™ DPE is available for customer evaluation. It runs on the Linux operating system with no special hardware requirements.

About Anchor Semiconductor

Founded in late 2000 and headquartered in Santa Clara, California, Anchor Semiconductor, Inc. is a pioneer and technology leader in design aware semiconductor manufacturing software products for advanced applications in layout-to-silicon pattern transfer. The integrated pattern-centric NanoScope™ platform is uniquely capable of providing solutions to the patterning and yield challenges in semiconductor design hot-spot checking, OPC and OPC verification, photomask making, silicon wafer printing and defect inspection. Using Anchor's tools,

customers have successfully shortened time-to-yield and time-to-profitability. For more information, please visit www.anchorsemi.com

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